

CUS150M1

RELIABILITY DATA

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※ Test results are typical data. Nevertheless the following results are considered to be actual capability data because all units have nearly the same characteristics.

1. Calculated Values of MTBF

MODEL : CUS150M1-12

(1) Calculating Method

Calculated based on part count reliability projection of JEITA (RCR-9102B). Individual failure rates λ_G is given to each part and MTBF is calculated by the count of each part.

$$MTBF = \frac{1}{\lambda_{equip}} = \frac{1}{\sum_{i=1}^n n_i (\lambda_G \pi_Q)_i} \times 10^6 \quad (\text{Hours})$$

λ_{equip} : Total Equipment Failure Rate (Failure/ 10^6 Hours)

λ_G : Generic Failure Rate for The ith Generic Part (Failure/ 10^6 Hours)

n_i : Quantity of ith Generic Part

n : Number of Different Generic Part Categories

π_Q : Generic Quality Factor for The ith Generic Part ($\pi_Q=1$)

(2) MTBF Values

G_F : Ground, Fixed

RCR-9102B

MTBF ≈ 145,065 (Hours)

2. Components Derating

MODEL : CUS150M1-12

(1) Calculating Method

(a) Measuring method

• Mounting method : Standard mounting A	• Ambient temperature : 50°C
• Input voltage : 115, 230VAC	• Output voltage & current : 12V, 12.5A(100%)

(b) Semiconductors

Compared with maximum junction temperature and actual one which is calculated based on case temperature, power dissipation and thermal impedance.

(c) IC, Resistors, Capacitors, etc.

Ambient temperature, operating condition, power dissipation and so on are within derating criteria.

(d) Calculating method of thermal impedance

$$\theta_{j-c} = \frac{T_j(\max) - T_c}{P_{ch}(\max)} \quad \theta_{j-a} = \frac{T_j(\max) - T_a}{P_{ch}(\max)} \quad \theta_{j-l} = \frac{T_j(\max) - T_l}{P_{ch}(\max)}$$

Tc : Case Temperature at Start Point of Derating ; 25°C in General

Ta : Ambient Temperature at Start Point of Derating ; 25°C in General

Tl : Lead Temperature at Start Point of Derating ; 25°C in General

Pch(max) : Maximum Channel Dissipation

Tj(max) : Maximum Junction (channel) Temperature
(Tch(max))

θ_{j-c} : Thermal Impedance between Junction (channel) and Case
(θ_{ch-c})

θ_{j-a} : Thermal Impedance between Junction and air

θ_{j-l} : Thermal Impedance between Junction and Lead

(2) Component Derating List

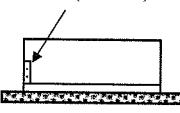
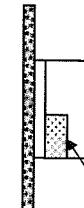
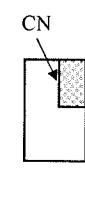
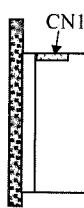
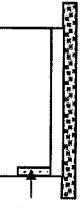
Location No.	Vin = 115VAC Mounting : A	Vout = 12V	Iout = 12.5A	Ta = 50°C
D1 D10XB60H-7000 SHINDENGEN	Tch (max) = 150 °C Pch = 3.01 W Tch = Tc+ ((θch-c) × Pch) = 120.3 °C D.F. = 80.2 %	θch-c = 1.9 °C/W ΔTc = 64.6 °C Tc = 114.6 °C		
Q1 TK16A60W TOSHIBA	Tch (max) = 150 °C Pch = 2.6 W Tch = Tc+ ((θch-c) × Pch) = 123.3 °C D.F. = 82.2 %	θch-c = 3.13°C/W ΔTc = 65.2 °C Tc = 115.2 °C		
D2 YG975C6R SHINDENGEN	Tj (max) = 150 °C Pd = 0.6 W Tch = Tc+ ((θj-c) × Pch)= 115.4 °C D.F. = 76.9 %	θj-c = 1.75°C/W ΔTc = 64.3 °C Tc = 114.3 °C		
Q2A TK7A60W TOSHIBA	Tj (max) = 150 °C Pd = 0.8 W Tj = Tc + ((θch-c) × Pd) = 114.6 °C D.F. = 76.4 %	θch-c = 4.17°C/W ΔTc = 61.3 °C Tc = 111.3 °C		
Q51A TK58A06N1 TOSHIBA	Tj (max) = 150 °C Pd = 0.45W Tj = Tc + ((θch-c) × Pd) = 98.1 °C D.F. = 56.1 %	θch-c = 3.57°C/W ΔTc = 46.5 °C Tc = 108.2 °C		

Location No.	Vin = 230VAC Mounting : A	Vout = 12V	Iout = 12.5A	Ta = 50°C
D1 D10XB60H-7000 SHINDENGEN	Tch (max) = 150 °C Pch = 1.5 W Tch = Tc+ ((θch-c) × Pch)= 105.5 °C D.F. = 70.3 %	θch-c = 1.9 °C/W ΔTc = 52.6 °C Tc = 102.6 °C		
Q1 TK16A60W TOSHIBA	Tch (max) = 150 °C Pch = 1.6 W Tch= Tc+ ((θch-c) × Pch)= 112.8 °C D.F. = 75.2 %	θch-c = 3.13°C/W ΔTc = 57.8 °C Tc = 107.8 °C		
D2 YG975C6R SHINDENGEN	Tj (max) = 150 °C Pd = 0.6 W Tch = Tc+ ((θj-c) × Pch) = 106.5 °C D.F. = 71.0 %	θj-c = 1.75°C/W ΔTc = 55.4 °C Tc = 105.4 °C		
Q2A TK7A60W TOSHIBA	Tj (max) = 150 °C Pd = 0.8 W Tj = Tc + ((θch-c) × Pd) = 106.5 °C D.F. = 71.0 %	θch-c = 4.17°C/W ΔTc = 53.2 °C Tc = 92.5 °C		
Q51A TK58A06N1 TOSHIBA	Tj (max) = 150 °C Pd = 0.45W Tj = Tc + ((θch-c) × Pd) = 97.2 °C D.F. = 55.6 %	θch-c = 3.57°C/W ΔTc = 45.6 °C Tc = 107.3 °C		

3. Main Components Temperature Rise ΔT List

MODEL : CUS150M1-12

(1) Measuring Conditions

Mounting Method	Mounting A	Mounting B	Mounting C	Mounting D	Mounting E
(Standard Mounting : A)	CN1(INPUT) 		CN 		
Input Voltage	115VAC				
Output Voltage	12VDC				
Output Current	12.5A(100%)				

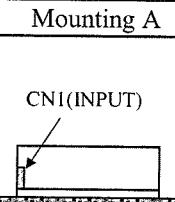
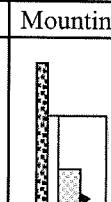
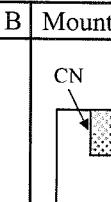
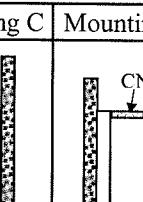
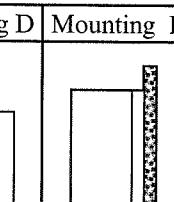
(2) Measuring Results

Output Derating		ΔT Temperature Rise ($^{\circ}$ C)				
		Io=12.5A (100 %)				
Location No.	Part name	Mounting A	Mounting B	Mounting C	Mounting D	Mounting E
C7	E.CAP.	41.4	36.3	46.7	42.4	42.1
C51B	E.CAP.	40.7	39.5	34.5	36.4	41.4
C51C	E.CAP.	35.9	37.8	28.9	31.1	38.3
C52	E.CAP.	34.6	34.5	28.9	30.1	36.5
L1 WIRE	BALUN COIL	39.7	30.4	49.7	44	35.4
L2 WIRE	BALUN COIL	43.3	32.3	50.5	45.6	37.9
L3 WIRE	CHOKE COIL	42.3	38.9	42.7	54.7	41.9
L4 WIRE	CHOKE COIL	70	71.7	64.6	71	70.5
L5 WIRE	CHOKE COIL	47.4	44	44.5	43.4	53.5
T1 WIRE	TRANSFORMER WIRE	56.6	53.6	52.1	52	53.5
T2 WIRE	TRANSFORMER WIRE	26.6	39.3	23.6	24.4	44.3
D1	BRIDGE DIODE	64.6	61.4	62.8	64.9	64.6
D2	S.B.D	64.3	64.1	61.5	63.9	68.1
D61	S.B.D	25.6	37.6	21.5	24.3	40.3
Q1	MOSFET	65.2	64.6	62.3	64.5	68.2
Q2A	MOSFET	61.3	62.8	58.6	61.1	66.3
Q2B	MOSFET	58.9	60.8	56.2	57.9	64.3
Q51A	MOSFET	43.8	40.7	45.8	40	43.4
Q51B	MOSFET	46.5	42.8	48.5	42.8	44.8
PC101	PHOTO COUPLER	41.5	43.6	35.1	35.1	49.2
PC102	PHOTO COUPLER	37.5	42.7	30.9	31.4	49.3
PC104	PHOTO COUPLER	30	40.6	24.1	25.2	47
A101	CHIP IC	46.8	37.3	50.9	43.1	41.5
A102	CHIP IC	51.9	51.4	47.9	47.4	59
A103	CHIP IC	45.3	39.9	40.7	41.8	46.1

3. Main Components Temperature Rise ΔT List

MODEL : CUS150M1-12

(1) Measuring Conditions

Mounting Method	Mounting A	Mounting B	Mounting C	Mounting D	Mounting E
(Standard Mounting : A)					
Input Voltage	230VAC				
Output Voltage	12VDC				
Output Current	12.5A(100%)				

(2) Measuring Results

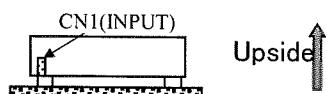
Output Derating		ΔT Temperature Rise (°C)				
		Io=12.5A (100 %)				
Location No.	Part name	Mounting A	Mounting B	Mounting C	Mounting D	Mounting E
C7	E.CAP.	37	31.3	40.8	38.1	34.8
C51B	E.CAP.	40.9	38.9	34	35.7	39.7
C51C	E.CAP.	35.3	37.1	28.4	30.5	36.3
C52	E.CAP.	34	34	28.4	29.4	34.8
L1 WIRE	BALUN COIL	25.7	18	33.8	31	21.2
L2 WIRE	BALUN COIL	31.9	22.4	37.8	35.4	26.9
L3 WIRE	CHOKE COIL	28.8	26.1	28.5	39.7	27.8
L4 WIRE	CHOKE COIL	54.6	56.4	50.2	56.4	54.4
L5 WIRE	CHOKE COIL	43.7	40.4	40.9	40.3	47.2
T1 WIRE	TRANSFORMER WIRE	55.5	52.5	51.3	51.3	51.2
T2 WIRE	TRANSFORMER WIRE	24.8	37.2	21.9	22.9	38.8
D1	BRIDGE DIODE	51.6	49.5	50	52.6	50.5
D2	S.B.D	55.4	55.5	53.1	55.9	57.2
D61	S.B.D	24.9	36.6	20.8	23.8	36.8
Q1	MOSFET	57.8	56.7	55.3	59.1	58.7
Q2A	MOSFET	53.2	54.4	50.9	53.8	56
Q2B	MOSFET	51.4	53.1	49.1	51.2	54.6
Q51A	MOSFET	43	40.1	44.8	39	41.9
Q51B	MOSFET	45.6	42.1	47.3	41.8	43.1
PC101	PHOTO COUPLER	39.6	41.8	33.6	33.8	44.2
PC102	PHOTO COUPLER	35.5	40.6	29.3	30.1	43.7
PC104	PHOTO COUPLER	28.3	38.5	22.9	23.9	41.4
A101	CHIP IC	41.7	33.2	45.4	39.1	35.6
A102	CHIP IC	46.4	46	43	43.5	50.5
A103	CHIP IC	40.8	35.2	38.2	38.8	40.4

4. Electrolytic Capacitor Lifetime

MODEL : CUS150M1-12

Cooling condition : Convection cooling

Mounting A

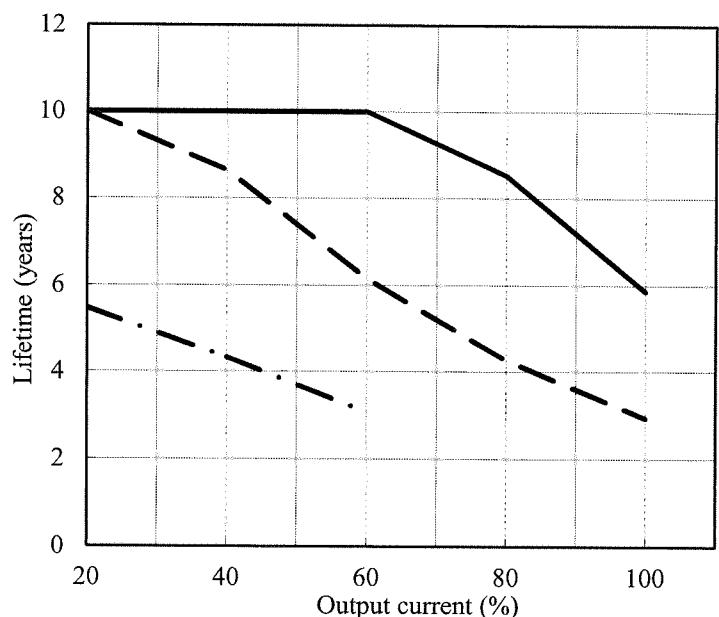


Vin=115VAC

Load (%)	Lifetime (years)		
	Ta= 40°C	Ta= 50°C	Ta= 60°C
20	10.0	10.0	5.5
40	10.0	8.6	4.3
60	10.0	6.2	3.1
80	8.5	4.3	-
100	5.9	2.9	-

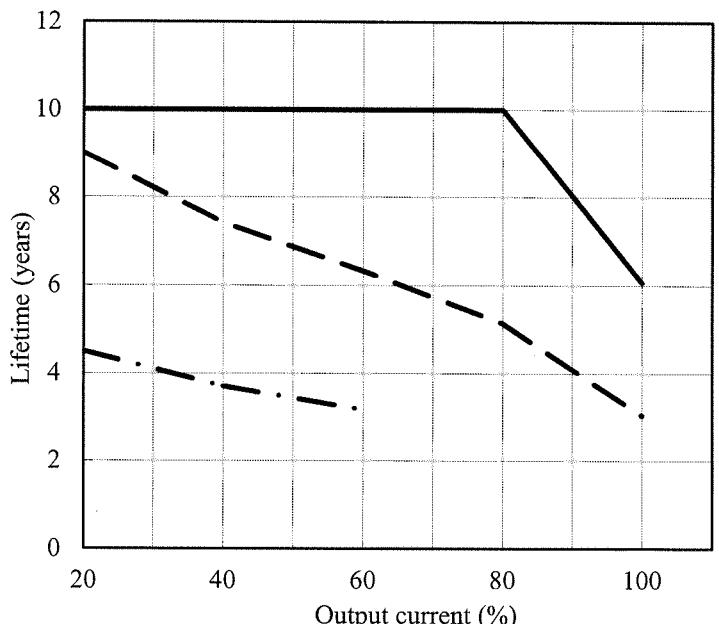
Conditions

Ta 40°C : —
50°C : - - -
60°C : - · -



Vin=230VAC

Load (%)	Lifetime (years)		
	Ta= 40°C	Ta= 50°C	Ta= 60°C
20	10.0	9.0	4.5
40	10.0	7.4	3.7
60	10.0	6.3	3.2
80	10.0	5.1	-
100	6.1	3.0	-

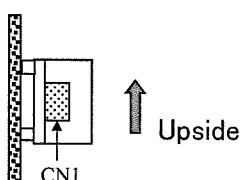


4. Electrolytic Capacitor Lifetime

MODEL : CUS150M1-12

Cooling condition : Convection cooling

Mounting B

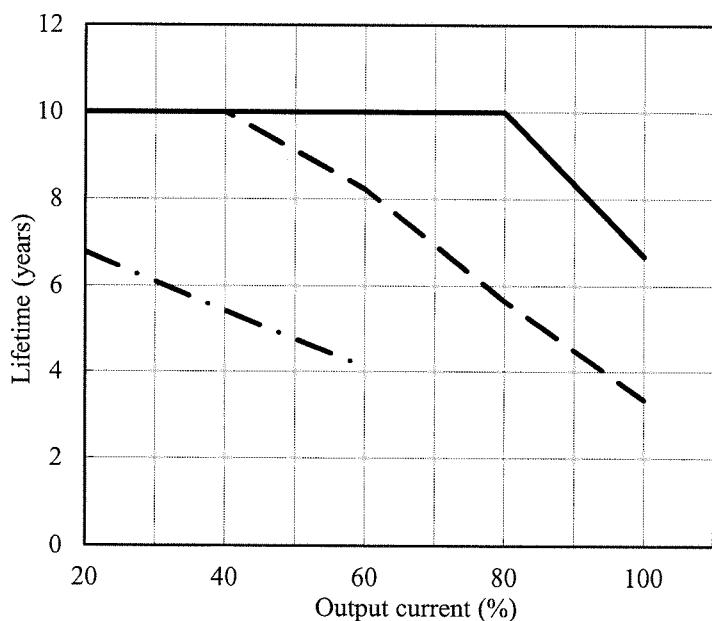


Vin=115VAC

Load (%)	Lifetime (years)		
	Ta= 40°C	Ta= 50°C	Ta= 60°C
20	10.0	10.0	6.8
40	10.0	10.0	5.4
60	10.0	8.2	4.1
80	10.0	5.7	-
100	6.7	3.3	-

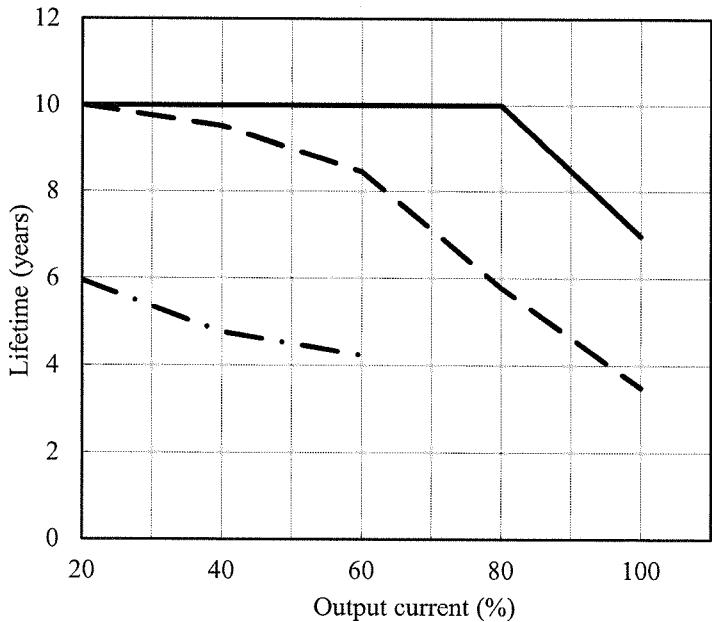
Conditions

Ta 40°C : ——
 50°C : - - -
 60°C : - · -



Vin=230VAC

Load (%)	Lifetime (years)		
	Ta= 40°C	Ta= 50°C	Ta= 60°C
20	10.0	10.0	5.9
40	10.0	9.5	4.8
60	10.0	8.5	4.2
80	10.0	5.8	-
100	7.0	3.5	-

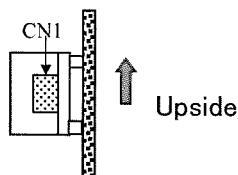


4. Electrolytic Capacitor Lifetime

MODEL : CUS150M1-12

Cooling condition : Convection cooling

Mounting C

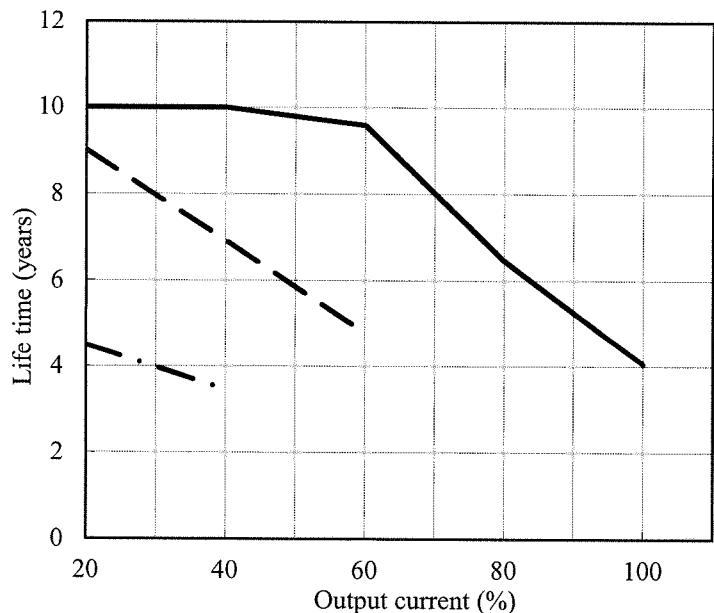


Vin=115VAC

Load (%)	Lifetime (years)		
	Ta= 40°C	Ta= 50°C	Ta= 60°C
20	10.0	9.0	4.5
40	10.0	6.9	3.5
60	9.6	4.8	-
80	6.5	-	-
100	4.1	-	-

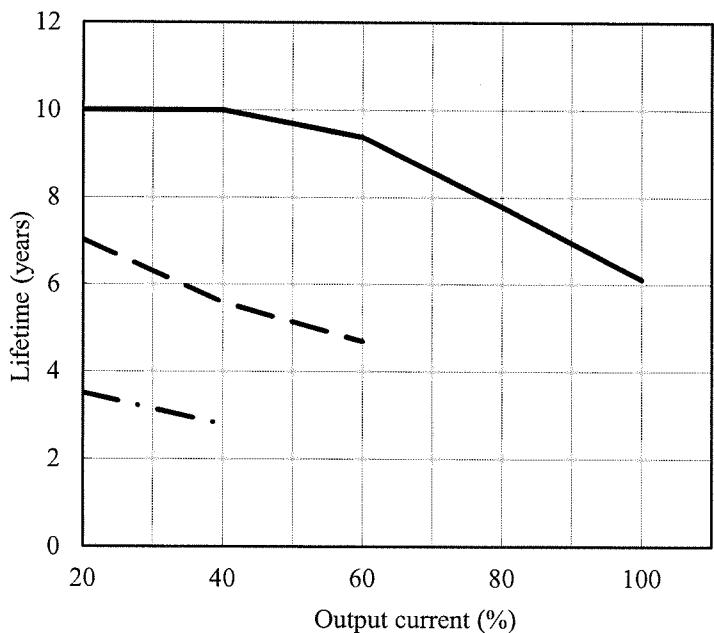
Conditions

Ta 40°C : —
50°C : - - -
60°C : - · -



Vin=230VAC

Load (%)	Lifetime (years)		
	Ta= 40°C	Ta= 50°C	Ta= 60°C
20	10.0	7.0	3.5
40	10.0	5.6	2.8
60	9.4	4.7	-
80	7.8	-	-
100	6.1	-	-

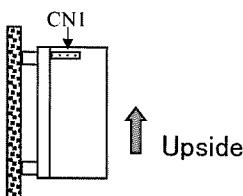


4. Electrolytic Capacitor Lifetime

MODEL : CUS150M1-12

Cooling condition : Convection cooling

Mounting D

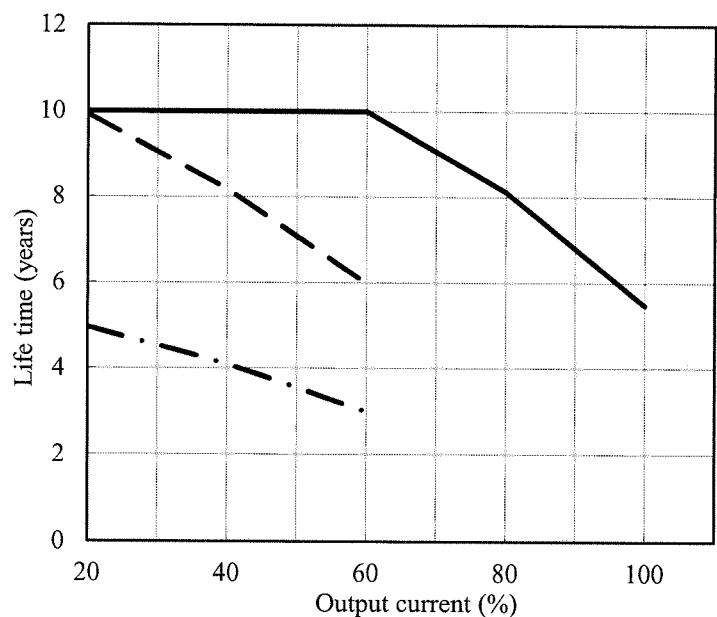


Vin=115VAC

Load (%)	Lifetime (years)		
	Ta= 40°C	Ta= 50°C	Ta= 60°C
20	10.0	9.9	5.0
40	10.0	8.2	4.1
60	10.0	6.0	3.0
80	8.1	-	-
100	5.5	-	-

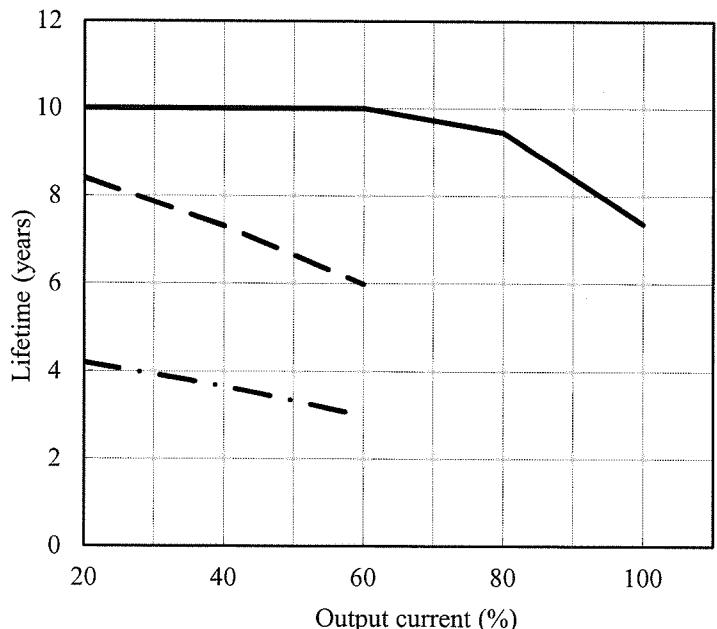
Conditions

Ta 40°C : —
50°C : - - -
60°C : - · -



Vin=230VAC

Load (%)	Lifetime (years)		
	Ta= 40°C	Ta= 50°C	Ta= 60°C
20	10.0	8.4	4.2
40	10.0	7.3	3.7
60	10.0	6.0	3.0
80	9.5	-	-
100	7.4	-	-

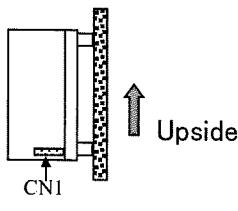


4. Electrolytic Capacitor Lifetime

MODEL : CUS150M1-12

Cooling condition : Convection cooling

Mounting E

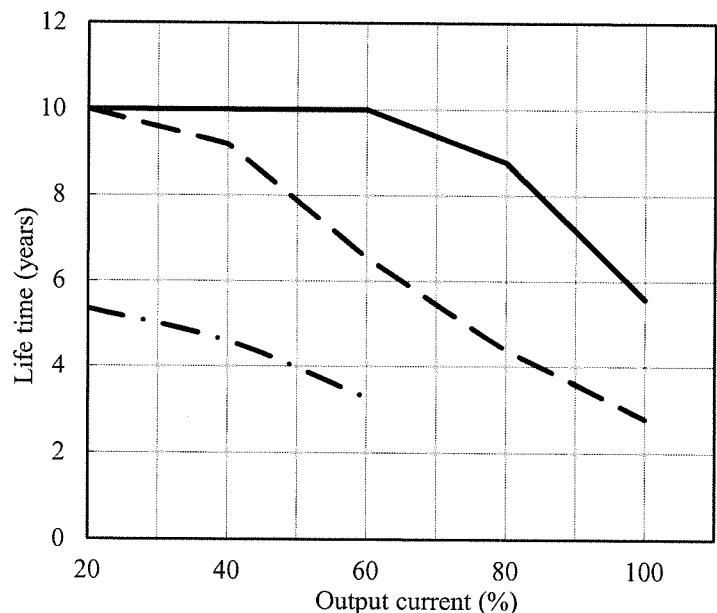


Vin=115VAC

Load (%)	Lifetime (years)		
	Ta= 40°C	Ta= 50°C	Ta= 60°C
20	10.0	10.0	5.4
40	10.0	9.2	4.6
60	10.0	6.5	3.3
80	8.8	4.4	-
100	5.6	2.8	-

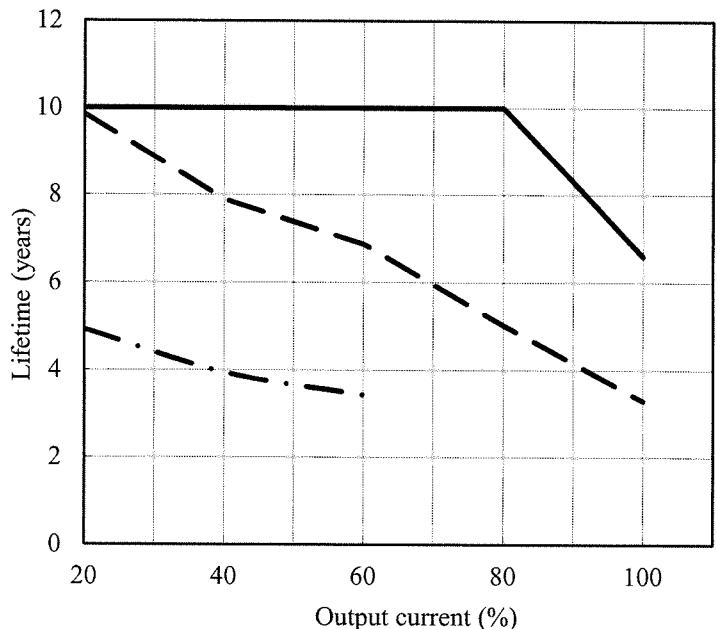
Conditions

Ta 40°C : ———
 50°C : - - -
 60°C : - · -



Vin=230VAC

Load (%)	Lifetime (years)		
	Ta= 40°C	Ta= 50°C	Ta= 60°C
20	10.0	9.9	4.9
40	10.0	7.9	3.9
60	10.0	6.9	3.4
80	10.0	5.0	-
100	6.6	3.3	-



5. Abnormal Test

MODEL :CUS150M1-12

(1) Test Conditions

Input : 230VAC Output : 12V, 12.5A Ta : 25°C

(2) Test Results

(Da : Damaged)

No.	Test position		Test mode		Test result												Others	Note
	Location No.	Test point	Short	Open	a Fire	b Smoke	c Burst	d Smell	e Red hot	f Damaged	g Fuse blown	h OVP	I OCP	j No output	k No change	l		
1	C1		○							○				○	○			
		1~3	○	○										○	○			
2	L1	1~3	○															
		1~3		○														
		2~4	○															
		2~4		○														
		1~2	○							○								
3	L2	1~3	○															
		1~3		○														
		2~4	○															
		2~4		○														
		1~2	○							○								
4	C4		○							○								
				○														
5	L3		○											○	○			
				○														
6	D1	AC~AC	○							○								
		AC~DC	○							○○								
		DC~DC	○							○○								
		AC		○										○○				
		DC+		○										○○○				
		DC-		○										○○○				
7	C6		○							○	○			○○				
				○						○	○			○○		○	Da : Q1 and Z101	
8	L4	1~2	○							○	○			○○		○	Da : Q1 and Z101	
		1~2		○										○○		○	Da : Q1 and Z101	
		3~4	○													○	Input power increase, audio noise	
		3~4		○						○				○○		○	Da : L4	
9	Q1	d		○										○○				
		s		○										○○				
		g		○										○○				
		d~s	○							○	○			○○		○	Da : Z101	
		g~s	○											○○				
		g~d	○							○	○			○○		○	Da : A101, Q1 and Z101	
10	D2		○							○	○			○○		○	Da : Q1 and Z101	
				○						○	○			○○		○	Da : Q1 and Z101	

5. Abnormal Test

MODEL :CUS150M1-12

(1) Test Conditions

Input : 230VAC Output : 12V, 12.5A Ta : 25°C

(2) Test Results

(Da : Damaged)

No.	Test position		Test mode	Test result													Note
	Locati on No.	Test point		Short	Open												
11	Q2A	d															
		s															
		g															
		d~s															
		g~s															
		g~d															
12	Q2B	d															
		s															
		g															
		d~s															
		g~s															
		g~d															
13	L5	d															
		s															
14	C8	g															
		d~s															
15	T2	g~s															
		g~d															
		1															
		2															
		3															
		4															
		6															
		7															
		1~2															
		2~3															
16	D61	3~4															
		6~7															
17	D101	1															
		2															
18	D107	3															
		4															
19	D109	5															
		6															
20	C7	7															
		8															

5. Abnormal Test

MODEL :CUS150M1-12

(1) Test Conditions

Input : 230VAC Output : 12V, 12.5A Ta : 25°C

(2) Test Results

(Da : Damaged)

No.	Test position		Test mode		Test result												Others	Note
	Location No.	Test point	Short	Open	a Fire	b Smoke	c Burst	d Smell	e Red hot	f Damaged	g Fuse blown	h OVP	I OCP	j No output	k No change	l		
21	D108		○															
22	Q51A	d										○						
		s		○○○								○○○						
		g										○○○						
		d~s	○									○○○						
		g~s	○									○○○					○ Input power Increase	
		g~d	○									○○○						
23	Q51B	d		○								○○○						
		s		○○								○○○						
		g		○								○○○						
		d~s	○									○○○						
		g~s	○									○○○					○ Input power Increase	
		g~d	○									○○○						
24	T1	2		○○														
		4		○○														
		7		○○○														
		8		○○○														
		A		○○○														
		B		○○○								○○○						
		11		○○○								○○○						
		12		○○								○○○						
		2~4	○									○○○						
		7,8~A	○									○○○						
25	C51B	B~11,12	○									○○○						
				○								○○○					○ Output ripple increase	
26	C51C		○									○○○					○ Output ripple increase	
				○								○○○					○ Output ripple increase	
27	C52		○									○○○					○ Output ripple increase	
				○								○○○						

6. Vibration Test

MODEL : CUS150M1-12

(1) Vibration Test Class

Frequency variable endurance test

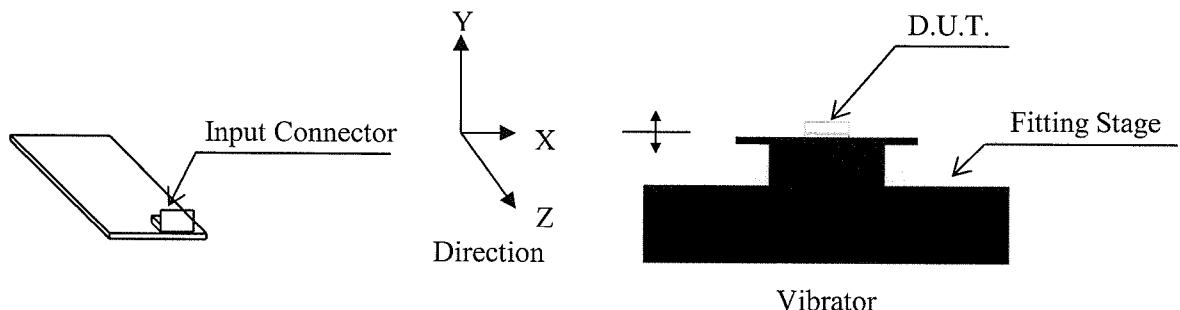
(2) Equipment Used

- Controller : DP550
DP CORP USA
- Vibrator : V870
LDS CORP. UK

(3) Test Conditions

- Sweep frequency : 10~55Hz
- Sweep time : 1.0min
- Acceleration : Constant 19.6m/s^2 (2G)
- Direction : X, Y, Z
- Sweep count : 1 hour each

(4) Test Method



(5) Acceptable Conditions

1. Not to be broken
2. Characteristic to be within regulation specification after the test.

(6) Test Results

OK

8. Thermal Shock Test

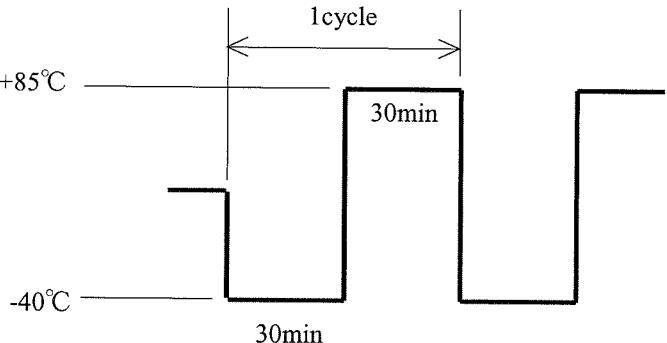
MODEL : CUS150M1-12

(1) Equipment Used

TSA-101S-W : ESPEC

(2) Test Conditions

- Ambient Temperature : -40°C \leftrightarrow 85°C +85°C
- Test Time : Refer to Dwg.
- Test Cycle : 200 Cycles
- No Operating



(3) Test Method

Before testing, check if there is no abnormal output, then put the D.U.T. in testing chamber, and test it according to the above cycle. 200 cycles later, leave it for 1 hour at the room temperature , then check if there is no abnormal output.

(4) Acceptable Conditions

1. Not to be broken
2. Characteristic to be within regulation specification after the test.

(5) Test Results

OK